

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 230420US41YA		SERIAL NO. 10/673,583	
LIST OF REFERENCES CITED BY APPLICANT		APPLICANT					
		Andrej S. MITROVIC					
		FILING DATE		GROUP			
		September 30, 2003		2128			
<b>U.S. PATENT DOCUMENTS</b>							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA	US 6,529,789	3/2003	Campbell, et al.			
	AB	US 6,618,856	9/2003	Coburn, et al.			
	AC	US 2005-0071037	3/31/2005	Strang			
	AD	US 2005-0071035	3/31/2005	Strang			
	AE	US 2005-0071038	3/31/2005	Strang			
	AF	US 2005-0071036	3/31/2005	Mitrovic			
	AG	US 2005-0071039	3/31/2005	Mitrovic			
	AH	US 6,198,980 B1	3/2001	Costanza, John R.			
	AI	US 7,107,571 B2	9/2006	Chang, et al.			
	AJ	US 5,741,070	4/21/1998	Mehrdad Mahmud Moslehi			
	AK	US 2004/0058255	3/25/2004	Scott Jessen, et al			
	A1						
	AL						
	AM						
	AN						
<b>FOREIGN PATENT DOCUMENTS</b>							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION		
					YES	NO	
	AO	CN 1335558A	2/13/2002	China (with Partial English Translation)	X		
	AP	WO 02/07210 A2	1/24/2002	WIPO		X	
	AQ	EP 0 718 595 A2	6/26/1996	EUROPE		X	
	AR	JP 2004-527117	9/2/2004	Japan (Corresponding Abstract from WO/02077589)		X	
	AS	WO 03/060779 A1	7/24/2003	WIPO		X	
	AT	JP 2005-515623	5/26/2005	JAPAN (With English Abstract)		X	
	AU	WO 03/009345 A2	1/30/2003	WIPO		X	
	AV	JP 2005-522018	7/21/2005	JAPAN (With English Abstract)		X	
<b>OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)</b>							
	AW	Agam SHAH, "TILERAS TARGETS INTEL, AMD WITH 100-CORE PROCESSOR", PCWorld Solved, IDG News October 26, 2009, pages 1-3					
	AX	Office Action issued March 30, 2011 in Japanese Patent Application No. 10-2006-7006632, (with English-language Translation) pages 1-17					
	AY	Su-shing CHEN, "AEMPES: An expert system for in-situ diagnostics and process monitoring", Semiconductor Manufacturing Science Symposium, 1990, IEEE/SEMI International, 21-23 May 1990, pages 119-122					
	AZ				<input type="checkbox"/> Additional References sheet(s) attached		
Examiner					Date Considered		
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

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		U.S. PATENT DOCUMENTS					
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AAA	US 2003/0003607	1/2/2003	Kagoshima et al			
	AAB	US 6,185,472	2/6/2001	Onga, et al.			
	AAC	US 7,047,095 B2	5/16/2006	Tomoyasu			
	AAD	US 6,587,744 B1	7/1/2003	Stoddard, et al.			
	AAE						
	AAF						
	AAG						
	AAH						
	AAI						
	AAJ						
	AAK						
	AAL						
	AAM						
	AAN						
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION		
	AAO	JP 2003-17471	1/17/2003	JAPAN (With English Abstract)	YES	NO	X
	AAP	WO 02/065511 A2	8/22/2002	WIPO			X
	AAQ	JP 2004-524685	8/12/2004	JAPAN			X
	AAR	WO 02/069063 A2	9/6/2002	WIPO			X
	AAS	JP 2004-531878	10/14/2004	JAPAN			X
	AAT	JP 2000-517473	12/26/2000	JAPAN (With English Abstract)			X
	AAU	WO 03/058699 A1	7/17/2003	WIPO			X
	AAV	JP 2005-514790	5/19/2005	JAPAN (With English Abstract)			X
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
	AAW	Naomi YONEMURA, et al., "HEAT ANALYSIS ON INSULATED METAL SUBSTRATES", Proc. Of the 1994 IMC, 100 (1994) pages 1407-1410					
	AAX	Office Action issued February 22, 2011 in Japanese Patent Application No. 2006-533881 (English-language) pages 1-9					
	AAY	Office Action issued September 7, 2007 in People's Republic of China Patent Application No. 2004 80028518.0 (with English-language translation) pages 1-62					
	AAZ	Office Action issued December 28, 2007 in People's Republic of China Patent Application No. 200480028479.4 (with English-language translation) pages 1-30				<input type="checkbox"/> Additional References sheet(s) attached	
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	AAAJ						
	AAAK						
	AAAL						
	AAAM						
	AAAN						
<b>FOREIGN PATENT DOCUMENTS</b>							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION		
	AAAO	JP 2002-367875	12/20/2002	JAPAN (With English Abstract)	YES	NO	X
	AAAP	JP 2003-502771	1/21/2003	JAPAN (With English Abstract)	YES	NO	X
	AAAQ	WO 02/077589 A2	10/3/2002	WIPO	YES	NO	X
	AAAR	KR 1999-071784	4/2/1999	Korea (with corresponding to US. Patent Application No. 5,719,796 attached as a courtesy herewith)	YES	NO	X
	AAAS	JP 11-330449	11/30/1999	JAPAN (with English Abstract)	YES	NO	X
	AAAT	JP 2000-269105	9/29/2000	JAPAN (with English Abstract)	YES	NO	X
	AAAU	JP 081484400 A	6/7/1996	JAPAN (with English Abstract)	YES	NO	X
	AAAV	JP 2000-517473	12/26/2000	JAPAN (with English Abstract from Corresponding Case)	YES	NO	X
	AAAW	JP 11-176906	7/2/1999	JAPAN (with English Abstract)	YES	NO	X
	AAAX				YES	NO	
<b>OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)</b>							
	AAAY	Office Action issued June 19, 2009 in The People's Republic of China Patent Application No. 200480028517.6 (with English-language translation) pages 1-38					
	AAAZ	Heru SETYAWAN, et al. "VISUALIZATION AND NUMERICAL SIMULATION OF FINE PARTICLE TRANSPORT IN A LOW-PRESSURE PARALLEL PLATE CHEMICAL VAPOR DEPOSITION", Chemical Engineering Science 57 (2002) pages 497-506					
						<input type="checkbox"/> Additional References sheet(s) attached	
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